

Class	Subclass
ISSUE CLASSIFICATION	

PATENT NUMBER

U.S. Utility Patent Application

SCANNED	O.I.P.E.	PAYMENT DATE

APPLICATION NO. 09/811915	CONT/PRIOR	CLASS 324	SUBCLASS 750	ART UNIT 2858 2829	EXAMINER N. N. N.
<p>APPLICANTS Wadgi Abadeer William Motsiff Edward Nowak</p> <p>TITLE Wafer level system for producing burn-in/screen, and reliability evaluations to be performed on all chips simultaneously without any wafer contacting</p>					

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